



First Semiconductor®

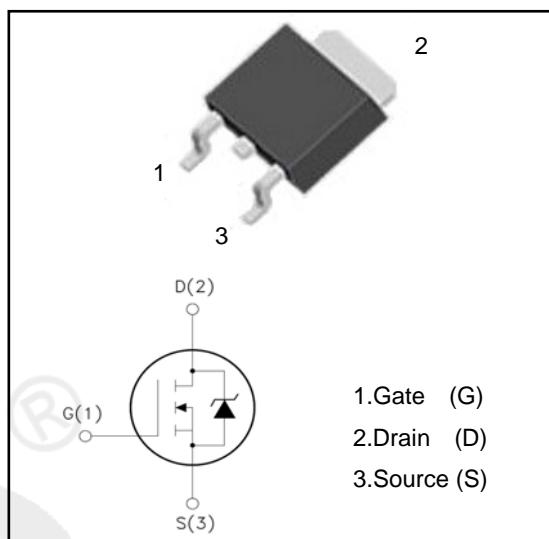
200V N-Channel MOSFET-C

FIR10N20LG

TO-252

Features

- Low Intrinsic Capacitances
- Excellent Switching Characteristics
- Extended Safe Operating Area
- Unrivalled Gate Charge : 22 nC (Typ.)
- BVDSS=200V, ID=10A
- Lower $R_{DS(on)}$: 0.4 Ω (Max) @VG=10V
- 100% Avalanche Tested



Absolute Maximum Ratings ($T_a=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	200	V
I_D	Drain Current	$T_j=25^\circ\text{C}$	10.0
		$T_j=100^\circ\text{C}$	7.0
$V_{GS(TH)}$	Gate Threshold Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	160	mJ
I_{AR}	Avalanche Current (note2)	9.0	A
P_D	Power Dissipation ($T_j=25^\circ\text{C}$)	72	W
T_j	Junction Temperature(Max)	150	°C
T_{stg}	Storage Temperature	-55~+150	°C
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	1.74	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	62.5	°C/W



Electrical Characteristics (Ta=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	ID=250 μ A, VGS=0	200	--	--	V
△BV _{DSS} / △T _J	Breakdown Voltage Temperature Conficient	I _D =250 μ A ,Reference to 25°C	--	0.55	--	V/°C
IDSS	Zero Gate Voltage Drain Current	Vds=200V, Vgs=0V	--	--	1	μ A
		Vds=160V, Tc=125°C			10	μ A
IGSSF	Gate-body leakage Current, Forward	Vgs=+30V, Vds=0V	--	--	100	nA
IGSSR	Gate-body leakage Current, Reverse	Vgs=-30V, Vds=0V	--	--	-100	nA
On Characteristics						
V _{GS(th)}	Date Threshold Voltage	Id=250uA,Vds=Vgs	2	--	4	V
R _{DS(on)}	Static Drain-Source On-Resistance	Id=4.5A,Vgs=10V	--	--	0.4	Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	VDS=25V, VGS=0, f=1.0MHz	--	710	-	pF
C _{oss}	Output Capacitance		--	85	-	pF
C _{rss}	Reverse Transfer Capacitance		--	22	-	pF
Switching Characteristics						
T _{d(on)}	Turn-On Delay Time	VDD=100V, ID=9A, RG=25 Ω (Note 3,4)	--	11	25	nS
T _r	Turn-On Rise Time		--	70	140	nS
T _{d(off)}	Turn-Off Delay Time		--	60	120	nS
T _f	Turn-Off Fall Time		--	65	130	nS
Q _g	Total Gate Charge	VDS=160,VGS=10V, ID=9A (Note 3,4)	--	22	30	nC
Q _{gs}	Gate-Source Charge		--	4	--	nC
Q _{gd}	Gate-Drain Charge		--	11	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I _s	Maximun Continuous Drain-Source Diode Forward Current	--	--	9	A	
I _{SM}	Maximun Plused Drain-Source DiodeForwad Current	--	--	36	A	
V _{SD}	Drain-Source Diode Forward Voltage	Id=9A	--	--	1.45	V
t _{rr}	Reverse Recovery Time	I _S =9.0A,V _{GS} =0V	--	140	--	nS
Q _{rr}	Reverse Recovery Charge	di _F /dt=100A/ μ S (Note3)	--	2.2	--	μ C

*Notes 1, L=8mH, IAS=9A, VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

Typical Characteristics

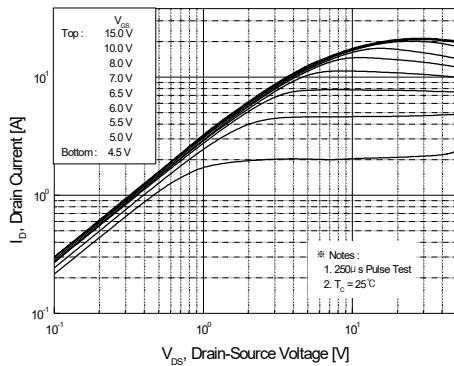


Figure 1. On-Region Characteristics

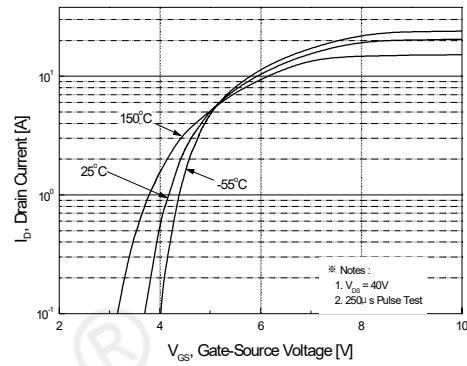


Figure 2. Transfer Characteristics

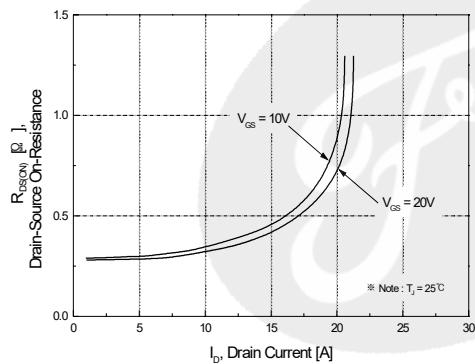


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

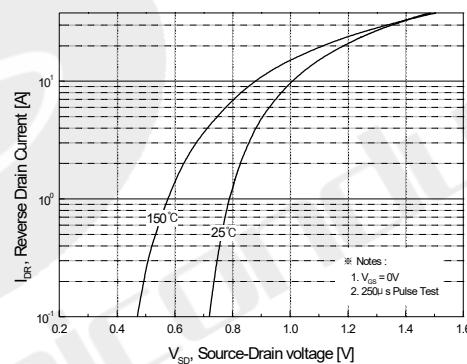


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

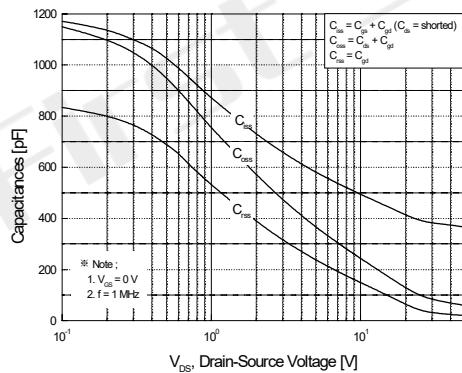


Figure 5. Capacitance Characteristics

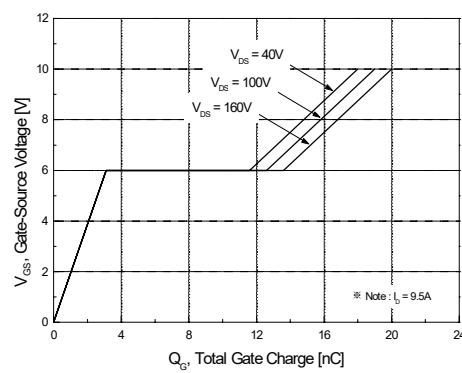


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

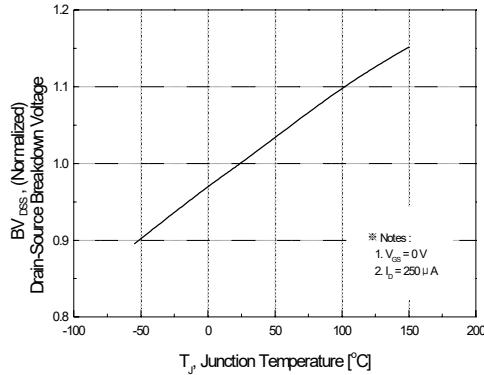


Figure 7. Breakdown Voltage Variation vs Temperature

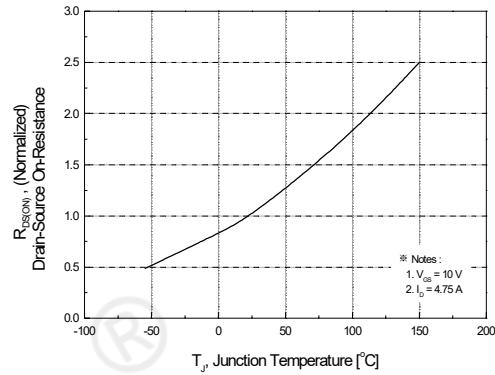


Figure 8. On-Resistance Variation vs Temperature

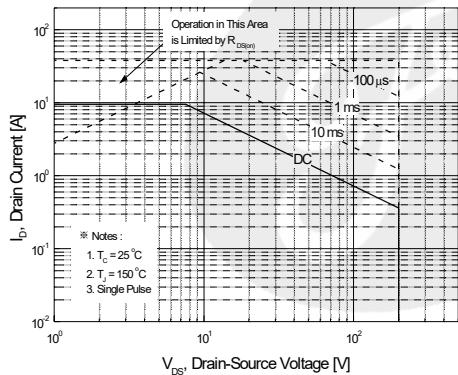


Figure 9-1. Maximum Safe Operating Area for WGP9N20

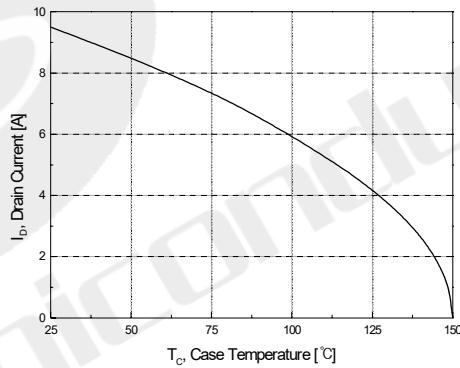


Figure 10. Maximum Drain Current vs Case Temperature

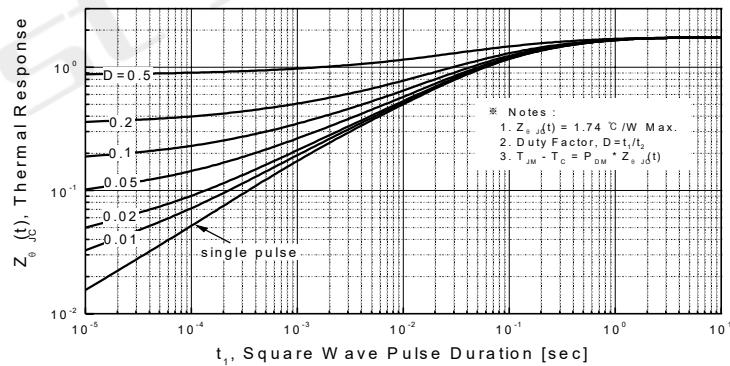
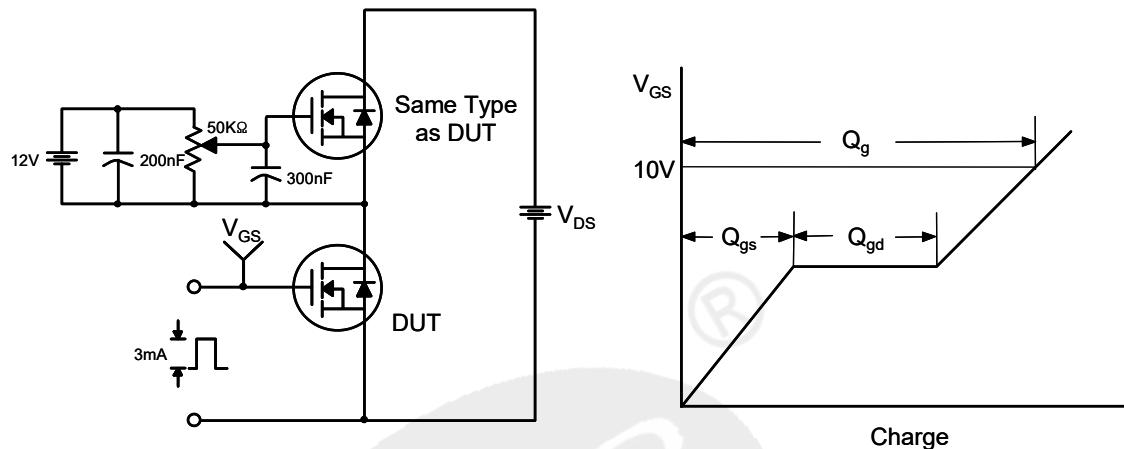
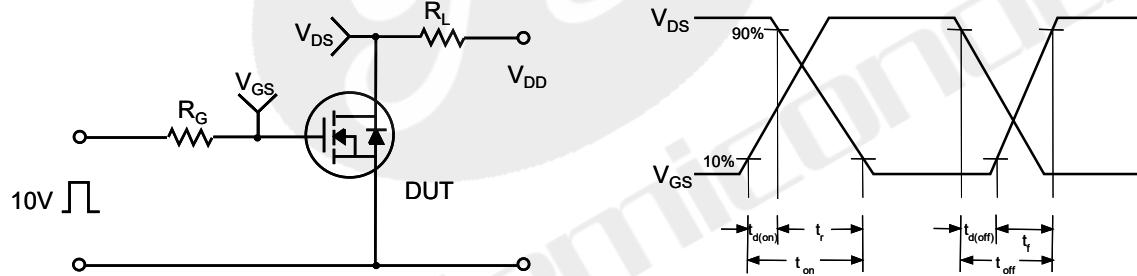
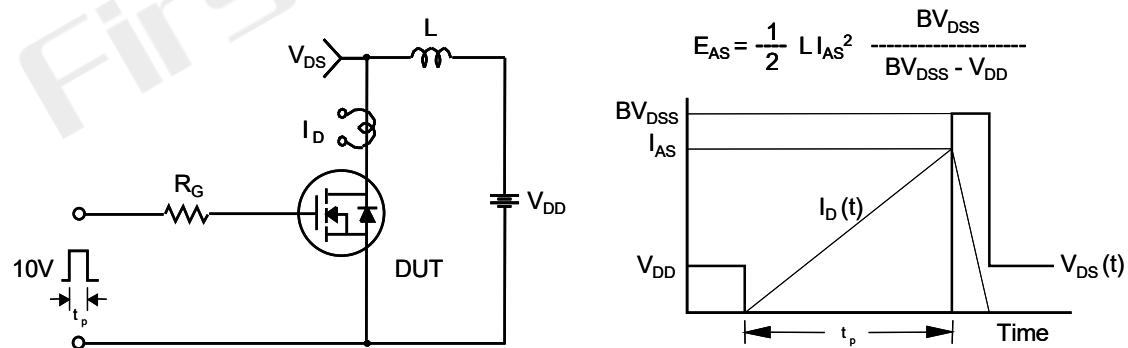
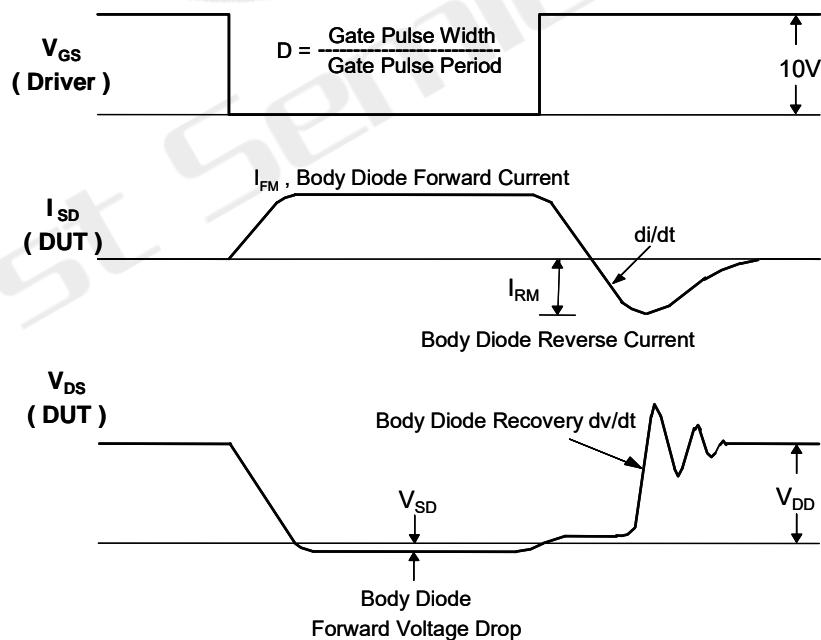
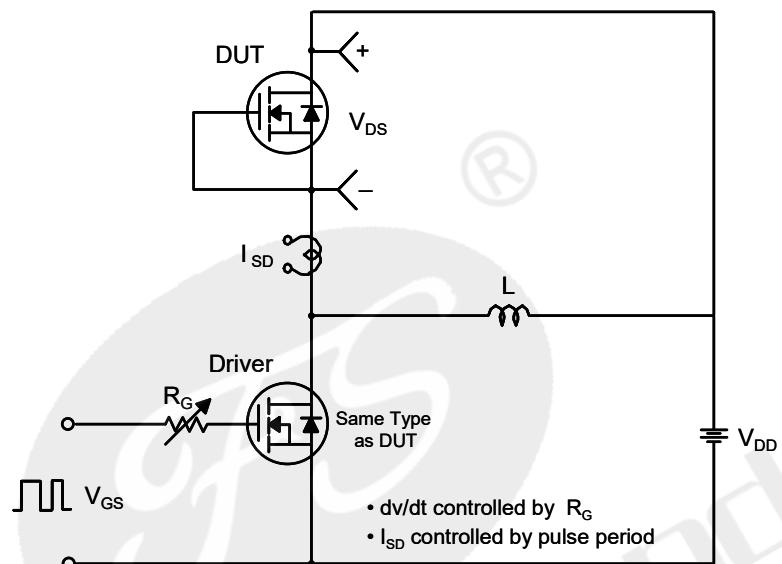


Figure 11-1. Transient Thermal Response Curve for WGP9N20

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms


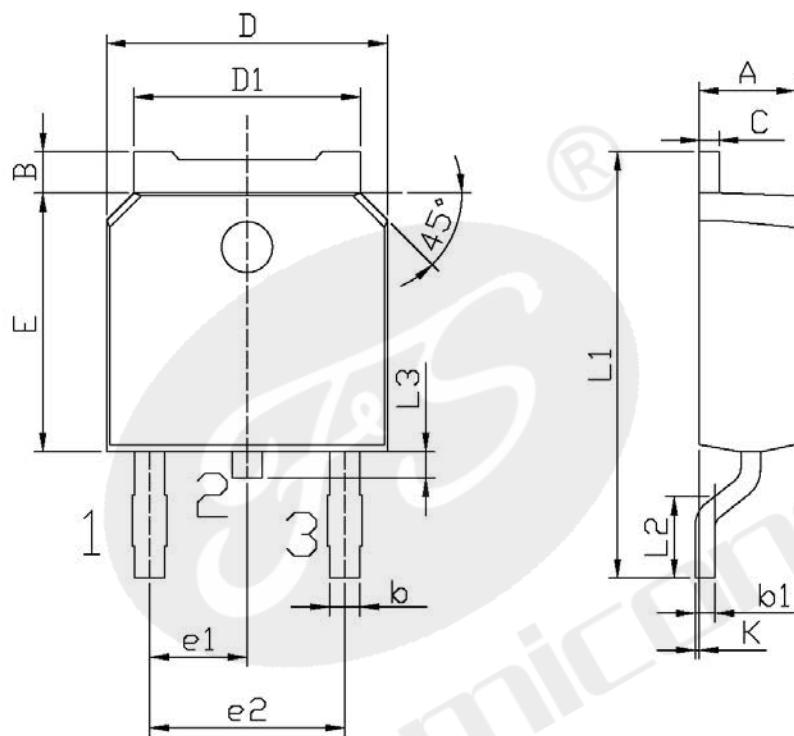
Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension

TO-252

Unit: mm



单位: mm

Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	2.20	2.40	E	5.95	6.25
B	0.95	1.25	e1	2.24	2.34
b	0.70	0.90	e2	4.43	4.73
b1	0.45	0.55	L1	9.85	10.35
C	0.45	0.55	L2	1.25	1.75
D	6.45	6.75	L3	0.60	0.90
D1	5.20	5.40	K	0.00	0.10



Declaration

- FIRST reserves the right to change the specifications, the same specifications of products due to different packaging line mold, the size of the appearance will be slightly different, shipped in kind, without notice! Customers should obtain the latest version information before ordering, and verify whether the relevant information is complete and up-to-date.
- Any semiconductor product under certain conditions has the possibility of failure or failure, The buyer has the responsibility to comply with safety standards and take safety measures when using FIRST products for system design and manufacturing, To avoid potential failure risks, which may cause personal injury or property damage!
- Product promotion endless, our company will wholeheartedly provide customers with better products!

ATTACHMENT

Revision History

Date	REV	Description	Page
2019.01.01	1.0	Initial release	